

S70GL02GP

2 Gbit, 3V Page Mode S70GL-P MirrorBit[®] Flash

General Description

The Cypress S70GL02GP 2 Gbit Mirrorbit Flash device is fabricated on 90-nm process technology. This device offers a fast page access time of 25 ns with a corresponding random access time of 110 ns. It features a Write Buffer that allows a maximum of 32 words/64 bytes to be programmed in one operation, resulting in faster effective programming time than standard single byte/word programming algorithms. This makes the device an ideal product for today's embedded applications that require higher density, better performance and lower power consumption.

This document contains information for the S70GL02GP device, which is a dual die stack of two S29GL01GP die. For detailed specifications, refer to the discrete die datasheet provided in Table 1.

Table 1. Affected Documents/Related Documents

| Title | Publication Number |
|--|--------------------|
| S29GL01GP, S29GL512P, S29GL256P, S29GL128P 1 Gbit, 512, 256, 128 Mbit, 3 V, Page Flash with 90 nm MirrorBit Process Technology | 002-00886 |

Distinctive Characteristics

- Two 1024 Mbit (S29GL01GP) in a single 64-ball Fortified-BGA package (see S29GL01P datasheet for full specifications)
- Single 3V read/program/erase (3.0V 3.6V)
- 90 nm MirrorBit process technology
- 8-word/16-byte page read buffer
- 32-word/64-byte write buffer reduces overall programming time for multiple-word writes
- Secured Silicon Sector region
 - 128-word/256-byte sector for permanent, secure identification through an 8-word/16-byte random Electronic Serial Number
 - Can be programmed and locked at the factory or by the customer
- Uniform 64Kword/128KByte Sector Architecture
 - S70GL02GP: two thousand forty-eight sectors
- 100,000 erase cycles per sector typical
- 20-year data retention typical
- Offered Packages
 - 64-ball Fortified BGA

- Suspend and Resume commands for Program and Erase operations
- Write operation status bits indicate program and erase operation completion
- Unlock Bypass Program command to reduce programming time
- Support for Common Flash Interface (CFI)
- Persistent and Password methods of Advanced Sector Protection
- WP#/ACC input
 - Accelerates programming time (when V_{ACC} is applied) for greater throughput during system production
 - Protects first or last sector of each die, regardless of sector protection settings
- Hardware reset input (RESET#) resets device
- Ready/Busy# output (RY/BY#) detects program or erase cycle completion

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Performance Characteristics

| Max. Read Access Times (ns)(Note 1) | | | | |
|--|------|--|--|--|
| Parameter | 2 Gb | | | |
| Random Access Time (t _{ACC}) | 110 | | | |
| Page Access Time (t _{PACC}) | 25 | | | |
| CE# Access Time (t _{CE}) | 110 | | | |
| OE# Access Time (t _{OE}) | 25 | | | |

Notes

1. Access times are dependent on V_{CC} and V_{IO} operating ranges. See Ordering Information on page 4 for further details.

2. Contact a sales representative for availability.

| Current Consumption (typical values) | | | | |
|--------------------------------------|-------|--|--|--|
| Random Access Read | 30 mA | | | |
| 8-Word Page Read | 1 mA | | | |
| Program/Erase | 50 mA | | | |
| Standby | 2 μΑ | | | |

| Program & Erase Times (typical values) | | | | |
|---|-------|--|--|--|
| Single Word Programming | 60 µs | | | |
| Effective Write Buffer Programming (V _{CC}) Per Word | 15 µs | | | |
| Effective Write Buffer Programming (V _{ACC}) Per Word | 15 µs | | | |
| Sector Erase Time (64 Kword Sector) | 0.5 s | | | |



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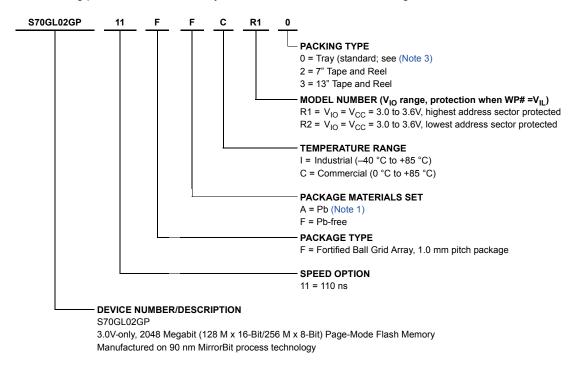
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1. Ordering Information

The ordering part number is formed by a valid combination of the following:



1.1 Recommended Combinations

Recommended Combinations table below list various configurations planned to be available in volume. The table below will be updated as new combinations are released. Check with your local sales representative to confirm availability of specific configuration not listed or to check on newly released combinations.

| S29GL-P Recommended Combinations (Note 1) | | | | | | |
|---|------------|----------------------------|--------------|--|--|--|
| Base OPN | Speed (ns) | Package and Temperature | Packing Type | Ordering Part Number (x = Packing Type) | | |
| S70GL02GP | 110 | FFC, FAC (Note 2) | R1, R2 | 0, 2, 3 (Note 3) | S70GL02GP11FFCR1x S70GL02GP11FFCR2x S70GL02GP11FACR1x S70GL02GP11FACR2x | |

Notes

2. BGA package marking omits leading "S29" and packing type designator from ordering part number.

3. Packing Type "0" is standard option.

^{1.} Contact a local sales representative for availability.



2. Input/Output Description and Logic Symbol

Table 1 identifies the input and output package connections provided on the device.

Table 1. Input/Output Description

| Symbol | Туре | Description | | | |
|-----------------|------------|---|--|--|--|
| A26–A0 | Input | Address lines for GL02GP | | | |
| DQ14–DQ0 | I/O | Data input/output. | | | |
| DQ15/A-1 | I/O | DQ15: Data input/output in word mode. | | | |
| DQISIA | 1/0 | A-1: LSB address input in byte mode. | | | |
| CE# | Input | Chip Enable. | | | |
| OE# | Input | Output Enable. | | | |
| WE# | Input | Write Enable. | | | |
| V _{CC} | Supply | Device Power Supply. | | | |
| V _{IO} | Supply | Versatile IO Input. | | | |
| V _{SS} | Supply | Ground. | | | |
| RY/BY# | Output | Ready/Busy. Indicates whether an Embedded Algorithm is in progress or complete. At V_{IL} , the device is actively erasing or programming. At High Z, the device is in ready. | | | |
| BYTE# | Input | Selects data bus width. At V _{IL} , the device is in byte configuration and data I/O pins DQ0-DQ7 are active. At V _{IH} , the device is in word configuration and data I/O pins DQ0-DQ15 are active. | | | |
| RESET# | Input | Hardware Reset. Low = device resets and returns to reading array data. | | | |
| WP#/ACC | Input | Write Protect/Acceleration Input. At V _{IL} , disables program and erase functions in the outermost sectors. At V _{HH} , accelerates programming; automatically places device in unlock bypass mode. Should be at V _{IH} for all other conditions. | | | |
| NC | No Connect | Not connected internally. | | | |

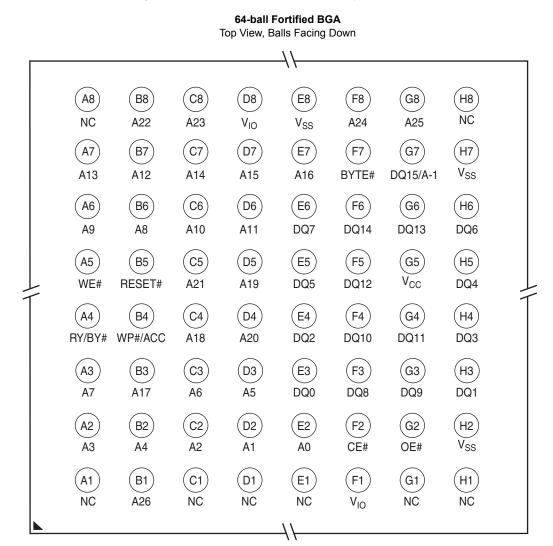


2.1 Special Handling Instructions for BGA Package

Special handling is required for Flash Memory products in BGA packages.

Flash memory devices in BGA packages may be damaged if exposed to ultrasonic cleaning methods. The package and/or data integrity may be compromised if the package body is exposed to temperatures above 150°C for prolonged periods of time.

Figure 2.1 64-ball Fortified Ball Grid Array





2.2 LSE064—64 ball Fortified Ball Grid Array, 13 × 11 mm

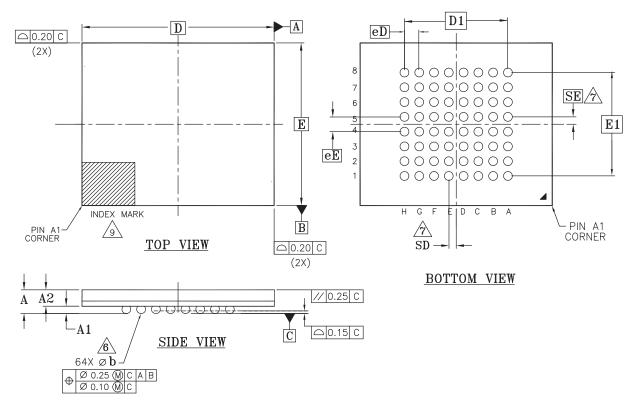


Figure 2.2 LSE064—64-ball Fortified Ball Grid Array (FBGA), 13 x 11 mm

| PACKAGE | | LSE 064 | | | |
|---------|--------------------------------|-----------|--------------------------|-------------------------|------------|
| JEDEC | N/A | | | | |
| D x E | 13.00 mm x 11.00 mm PACKAGE | |) mm | | |
| SYMBOL | MIN | NOM | MAX | NOTE | |
| A | | | 1.40 | PROFILE | |
| A1 | 0.40 | | | BALL HEIGHT | |
| A2 | 0.79 | | 0.91 | BODY THICKNESS | |
| D | 13.00 BSC. | | - | BODY SIZE | |
| E | 11.00 BSC. | | | BODY SIZE | |
| D1 | 7.00 BSC. | | | MATRIX FOOTPRINT | |
| E1 | 7.00 BSC. | | | MATRIX FOOTPRINT | |
| MD | | 8 | | MATRIX SIZE D DIRECTION | |
| ME | | 8 | | MATRIX SIZE E DIRECTION | |
| n | | 64 | | BALL COUNT | |
| Øb | 0.50 | 0.60 | 0.70 | BALL DIAMETER | |
| eE | 1.00 BSC. | | E 1:00 BSC. BAL | | BALL PITCH |
| eD | 1.00 BSC | | | BALL PITCH | |
| SD / SE | | 0.50 BSC. | | SOLDER BALL PLACEMENT | |
| | | | DEPOPULATED SOLDER BALLS | | |

NOTES:

- 1. DIMENSIONING AND TOLERANCING METHODS PER ASME Y14.5M-1994.
- 2. ALL DIMENSIONS ARE IN MILLIMETERS.
- 3. BALL POSITION DESIGNATION PER JEP95, SECTION 4.3, SPP-010.
- 4. e REPRESENTS THE SOLDER BALL GRID PITCH.
- 5. SYMBOL "MD" IS THE BALL MATRIX SIZE IN THE "D" DIRECTION.

SYMBOL "ME" IS THE BALL MATRIX SIZE IN THE "E" DIRECTION.

n IS THE NUMBER OF POPULTED SOLDER BALL POSITIONS FOR MATRIX SIZE MD X ME.

- DIMENSION "b" IS MEASURED AT THE MAXIMUM BALL DIAMETER IN A PLANE PARALLEL TO DATUM C.
- SD AND SE ARE MEASURED WITH RESPECT TO DATUMS A AND B AND DEFINE THE POSITION OF THE CENTER SOLDER BALL IN THE OUTER ROW.

WHEN THERE IS AN ODD NUMBER OF SOLDER BALLS IN THE OUTER ROW SD OR SE = 0.000.

- WHEN THERE IS AN EVEN NUMBER OF SOLDER BALLS IN THE OUTER ROW, SD OR SE = $\boxed{e/2}$
- 8. "+" INDICATES THE THEORETICAL CENTER OF DEPOPULATED BALLS.
- A1 CORNER TO BE IDENTIFIED BY CHAMFER, LASER OR INK MARK, METALLIZED MARK INDENTATION OR OTHER MEANS.

3611 \ 16-038.15 \ 11.13.6



3. Memory Map

The S70GL02GP consist of uniform 64 Kword (128 Kb) sectors organized as shown in Table 2.

Table 2. S70GL02GP Sector & Memory Address Map

| Uniform Sector Size | Sector Count | Sector Range | Address Range (16-bit) | Notes |
|---------------------|--------------|--------------|------------------------|-------------------------|
| | | SA00 | 0000000h-000FFFFh | Sector Starting Address |
| 64 Kword/128 Kb | 2048 | : | : | |
| | | SA2047 | 7FF0000H–7FFFFFFh | Sector Ending Address |

Note

This table has been condensed to show sector-related information for an entire device on a single page. Sectors and their address ranges that are not explicitly listed (such as SA001-SA2046) have sector starting and ending addresses that form the same pattern as all other sectors of that size. For example, all 128 Kb sectors have the pattern xxx0000h-xxxFFFFh.

4. Autoselect

Table 3 provides the device identification codes for the S70GL02GP. For more information on the autoselect function, refer to the S29GL01P datasheet.

| Description | Address | Read Data (word/byte mode) |
|-----------------------|--------------|--|
| Manufacturer ID | (Base) + 00h | xx01h/1h |
| Device ID, Word 1 | (Base) + 01h | 227Eh/7Eh |
| Device ID, Word 2 | (Base) + 0Eh | 2248h/48h |
| Device ID, Word 3 | (Base) + 0Fh | 2201h/01h |
| Secure Device Verify | (Base) + 03h | For S70GL02GPH: XX19h/19h = Not Factory Locked. XX99h/99h = Factory Locked. For S70GL02GPL: XX09h/09h = Not Factory Locked. XX89h/89h = Factory Locked. |
| Sector Protect Verify | (SA) + 02h | xx01h/01h = Locked, xx00h/00h = Unlocked |

Table 3. Autoselect Addresses in System

5. Erase And Programming Performance

Table 4. Erase And Programming Performance

| Paramet | Typ (Note 1) | Max (Note 2) | Unit | Comments | |
|---|--------------|--------------|------|----------|--|
| Sector Erase Time | | 0.5 | 3.5 | sec | Excludes 00h programming |
| Chip Erase Time | S70GL02GP | 1024 | 4096 | sec | prior to erasure (Note 3) |
| Total Write Buffer Time, for 64 bytes | | 480 | | μs | |
| Total Accelerated Write Buffer Programming Time, for 64 bytes | | 432 | | μs | Excludes system level overhead (Note 4) |
| Chip Program Time S70GL02GP | | 1968 | | sec | |

Notes

1. Typical program and erase times assume the following conditions: 25°C, 3.6 V V_{CC}, 10,000 cycles, checkerboard pattern.

2. Under worst case conditions of -40°C, V_{CC} = 3.0 V, 100,000 cycles.

3. In the pre-programming step of the Embedded Erase algorithm, all bits are programmed to 00h before erasure.

4. System-level overhead is the time required to execute the two- or four-bus-cycle sequence for the program command.



6. BGA Package Capacitance

| Parameter Symbol | Test Setup | Тур | Max | Unit | |
|------------------|---------------------------|----------------------|-----|------|----|
| C _{IN} | Input Capacitance | V _{IN} = 0 | 12 | 20 | pF |
| C _{OUT} | Output Capacitance | V _{OUT} = 0 | 20 | 24 | pF |
| C _{IN2} | Control Pin Capacitance | V _{IN} = 0 | 16 | 20 | pF |
| RESET#, WP#/ACC | Separated Control Pin | V _{IN} = 0 | 84 | 90 | pF |
| CE# | CE# Separated Control Pin | | 44 | 50 | pF |

Notes

1. Sampled, not 100% tested.

2. Test conditions $T_A = 25^{\circ}C$, f = 1.0 MHz.





7. Revision History

Document History Page

| lev. | ECN No. | Orig. of Change | Submission Date | Description of Change |
|------|---------|--------------------|--------------------|---|
| ** | _ | RYSU | 12/04/2006 | Initial release |
| *A | _ | RYSU | 05/19/2008 | Global: Changed data sheet designation Added Product Life-cycle notice Removed Table of Figures and Table of Tables Ordering Information: Changed sample OPN Added Commercial temperature range Changed configuration in "Device Number/description" Modified "Recommended Combination" table removed TSOP package option Erase And Program Performance: Chip Program Time - removed comment Common Flash Memory Interface: Removed section (see publication S29GL-P_00 for details) |
| *В | _ | RYSU | 02/23/2010 | Global: Updated available model options. Corrected Chip Program Time. |
| *C | 4950184 | RYSU | 10/06/2015 | Updated to Cypress template |
| *D | 5177489 | RYSU | 03/16/2016 | Updated General Description and Distinctive Characteristics. |
| *E | 5962352 | AESATMP8 | 11/09/2017 | Updated logo and Copyright. |



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